


<b>Search Notes</b>  	<b>Application/Control No.</b>  10700908	<b>Applicant(s)/Patent Under Reexamination</b>  RASPL, STEFAN
	<b>Examiner</b>  SUSAN Y CHEN	<b>Art Unit</b>  2161

SEARCHED			
Class	Subclass	Date	Examiner
707	1, 3, 6, 7, 101, 102	9/12/08	tyc
702	179, 190	9/12/08	tyc

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--